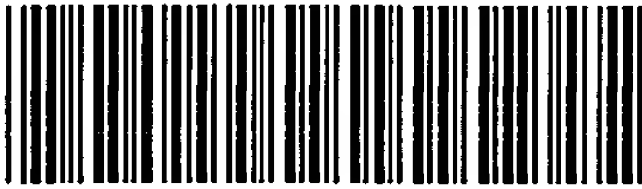


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/844,441	BUCHWALD ET AL.	
	Examiner	Art Unit	
	Eva Yi Zheng	2634	

SEARCHED			
Class	Subclass	Date	Examiner
375	355	7/21/2005	E.Z
375	335	7/21/2005	E.Z
375	362	7/21/2005	E.Z

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
updated EAST; IEEE	7/21/2005	E.Z